

RF Exposure Evaluation Report

Application No.:	DNT2410170162R2749-04502
Applicant:	Systec&Solutions
Address of Applicant:	Wilhelm-Schickard-Straße 9, Karlsruhe, Karlsruhe, Germany
EUT Description:	Wireless charger module
Model No.:	HG-EPP15W-V3.0
FCC ID:	2BMCR-HG-EPP15W-V3
Power supply	DC 24V
Trade Mark:	
Standards:	FCC CFR 47 Part 1.1307(b)&1.1310 KDB 680106 D01 Wireless Power Transfer v04
Date of Receipt:	2024/10/25
Date of Test:	2024/10/26 to 2024/11/4
Date of Issue:	2024/12/12
Test Result:	PASS *
Prepared By:	Wardne Jon (Testing Engineer)

Prepared By:	Wayne . Lon	(Testing Engineer)
Reviewed By:	Peneils . chen	(Project Engineer)
Approved By:	Here then	(Manager)



Note: If there is any objection to the results in this report, please submit a written inquiry to the company within 15 days from the date of receiving the report. The test report is effective only with both signature and specialized stamp, and is issued by the company in accordance with the requirements of the "Conditions of Issuance of Test Reports" printed in the attached page. Unless otherwise stated, the results presented in this report only apply to the samples tested this time. Partial reproduction of this report is not allowed unless approved by the company in writing.

Dongguan DN Testing Co., Ltd.

 Add: No. 1, West Fourth Street, Xingfa South Road, Wusha Community, Chang 'an Town, Dongguan City, Guangdong P.R.China

 Web: www.dn-testing.com

 Tel:+86-769-88087383

 E-mail: service@dn-testing.com



Report No.: DNT2410170162R2749-04502 Report Revise Record Date: December 12, 2024

Page: 2/11

Report Version	Revise Time	Issued Date	Valid Version	Notes
V1.0		Dec.12, 2024	Valid	Original Report



Page: 3 / 11

Test Summary

$\boldsymbol{<}$	No.	Description of Test Item	FCC Standard Section	Results
		Maximum Permissible Exposure	Part 1.1307(b)&1.1310	PASS



TEGT CUMANA DV

Report No.: DNT2410170162R2749-04502

Date: December 12, 2024

Page: 4 / 11

Contents

IESI SUMMARY	•••••••••••••••••		
1 GENERAL INFORMATION			
1.1 TEST LOCATION			\bigcirc
1.2 GENERAL DESCRIPTION OF EUT			
1.2 GENERAL DESCRIPTION OF EUT 1.3 TEST MODE 1.4 TEST EQUIPMENT LIST		<u> </u>	
1.4 Test Equipment List			
1.5 Assistant equipment used for test 1.6 Description of Support Units			
1.6 DESCRIPTION OF SUPPORT UNITS			7
1.7 Test Facility			
1.8 Measurement Uncertainty (95% confidence levels, k=2)			
2 MAXIMUM PERMISSIBLE EXPOSURE	<u> </u>	\square	
2.1 Limit 2.2 Test Setup A			
2.2 TEST SETUP A			9
2.3 TEST PROCEDURE			9
2.4 EQUIPMENT APPROVAL CONSIDERATIONS			10
2.5 TEST RESULT FOR TEST SETUP A:			11



1 General Information

1.1 Test Location

Company:	Dongguan DN Testing Co., Ltd
Address:	No. 1, West Fourth Street, South Xinfa Road, Wusha Liwu, Chang ' an Town, Dongguan City, Guangdong P.R.China
Test engineer:	Wayne Lin

1.2 General Description of EUT

Manufacturer:	Shenzhen Huagon Technology Co.,Ltd
Address of Manufacturer:	6 floor, Building A,Weihuada Industrial Park, No. 5, Lirong Road, Xinshi community, Dalang street, Longhua District, Shenzhen 518109
EUT Description::	Wireless charger module
Test Model No.:	HG-EPP15W-V3.0
Additional Model(s):	
Chip Type:	SC5004
Serial Number	PR2410170162R2749
Power Supply	DC 24V
Output Max Wireless Charge Power:	15W
Trade Mark:	N/A
Hardware Version:	V1.0
Software Version:	V1.0
Sample Type:	□ Portable Device, ⊠ Module, ⊠ Mobile Device
Antenna Type:	□ External, ⊠ Integrated

Remark:

*Since the above data and/or information is provided by the applicant relevant results or conclusions of this report are only made for these data and/or information, DNT is not responsible for the authenticity, integrity and results of the data and information and/or the validity of the conclusion.



1.3 Test Mode

Test Item	Test Mode
Maximum Permissible Exposure	Wireless Charging
Note: The worst Full Load status is recorded in the re	eport

1.4 Test Equipment List

Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
Electric and Magnetic Field Probe-Analyzer	Senfu STT	LF-04	l-1044	Oct 18,2024	Oct 17,2025

1.5

Assistant equipment used for test

Code	Equipment	Manufacturer	Model No.	Equipment No.
	iPhone	Apple	iPhone 14	NA 🕥



Date: December 12, 2024

1.6 Description of Support Units

The EUT has been tested independent unit.

1.7 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

Lab A:

• FCC, USA

Designation Number: CN1348

A2LA (Certificate No. 7050.01)

DONGGUAN DN TESTING CO., LTD. is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 7050.01.

Innovation, Science and Economic Development Canada

DONGGUAN DN TESTING CO., LTD. EMC Laboratory has been recognized by ISED as an accredited testing laboratory. CAB identifier is CN0149.

IC#: 30755.

1.8 Measurement Uncertainty (95% confidence levels, k=2)

No.	Item	Measurement Uncertainty
1	20dB Emission Bandwidth	±0.0196%
2	Carrier Frequency Separation	±1.9%
3	Number of Hopping Channel	±1.9%
4	Time of Occupancy	±0.028%
5	Max Peak Conducted Output Power	±0.743 dB
6	Band-edge Spurious Emission	±1.328 dB
7	Conducted RF Spurious Emission	9KHz-1GHz:±0.746dB
		1GHz-26GHz:±1.328dB

No.	Item	Measurement Uncertainty
1	Conduction Emission	± 3.0dB (150kHz to 30MHz)
$\langle \rangle$	2 Radiated Emission	± 4.8dB (Below 1GHz)
		± 4.8dB (1GHz to 6GHz)
2		± 4.5dB (6GHz to 18GHz)
		± 5.02dB (Above 18GHz)



2 Maximum Permissible Exposure

2.1 Limit

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm2)	Averaging time (minutes)	
5 5	(A) Limits for	Occupational/Contro	olled Exposure		
0.3-3.0	614	1.63	*100	6	
3.0-30 1842/f		4.89/f	*900/f ²	6	
30-300	61.4	0.163	1.0	6	
300-1,500		5 15	f/300	6	
1,500-100,000	/		5	6	
2 2	(B) Limits for Ger	eral Population/Unco	ontrolled Exposure	<u> </u>	
0.3-1.34	614	1.63	*100	30	
1.34-30 824/f		2.19/f	*180/f ²	30	
30-300	27.5	0.073	0.2	30	
300-1,500			f/1500	30	
1,500-100,000	1	1	1.0	30	

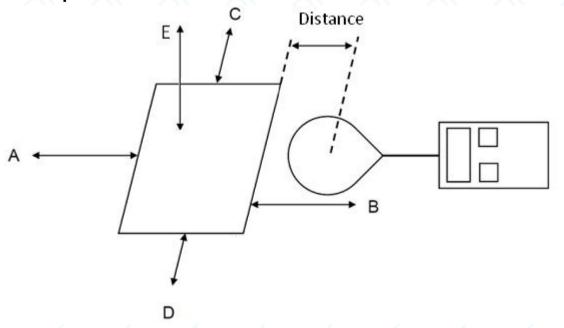
Limits for Maximum Permissible Exposure (MPE)

Note:

- 1. f = frequency in MHz * = Plane-wave equivalent power density.
- 2. For devices designed for typical desktop applications, such a wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m. A KDB inquiry is required to determine the applicable exposure limits below 100 kHz.



2.2 Test Setup A



2.3 Test Procedure

a. The test was performed on 360 degree turn table in anechoic chamber.

b. The probe was placed at 15 cm surrounding the device and 20 cm above the top of the charger and the geometric centre of the probe, for test setup A.

d. The highest emission level was recorded and compared with limit as soon as measurement of each point; A,

B, C, D, E were completed.



2.4 Equipment Approval Considerations

Inductive wireless power transfer applications with supporting field strength results and meeting all of the following requirements are not required to submit a KDB inquiry for devices approved using SDoC or a PAG for equipment approved using certification to address RF exposure compliance.

_	Power transfer frequency is less that 1 MHz
1	YES; the device operated in the frequency range from 110.5-205KHz.
2	Output power from each primary coil is less than or equal to 15 watts.
	YES; the maximum output power of the primary coil is 15W.
3	The system may consist of more than one source primary coils, charging one or more clients. If more than one primary coil is present, the coil pairs may be powered on at the same time.
	YES; the transfer system includes only single primary and secondary coils.
4	Client device is placed directly in contact with the transmitter.
	YES; Client device is placed directly in contact with the transmitter.
5	Mobile exposure conditions only (portable exposure conditions are not covered by this
	exclusion).
	YES.
6	The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top
	surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the
	MPE limit.
	YES; The EUT field strength levels are 50% x MPE limts.



Page: 11 / 11

2.5 Test Result for Test setup A:

E-fie	Distance(cm)			
Frequency range (KHz)	110.5 to 205			A'
Test Mode	Full Load		1	\sim
Position A(V/m)	2.788		15	\sim
Position B(V/m)	2.689		15	5
Position C(V/m)	2.358	~	15	× .
Position D(V/m)	2.126		15	
Position E(V/m)	6.614		20	
Limits (V/m)	614		1	×
50% Limits(V/m)	307			

H-field stre	Distance(cm)			
Frequency range (KHz)	110.5 to 205			
Test Mode	Full Load			
Position A(A/m)	0.011	15		
Position B(A/m)	0.021	15		
Position C(A/m)	0.024	15		
Position D(A/m)	0.019 📈	15		
Position E(A/m)	0.087	20		
Limits (A/m)	1.630			
50% Limits (A/m)	0.815			

---END REPORT---